

Si3454DV

N-Channel PowerTrench® MOSFET

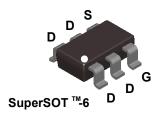
General Description

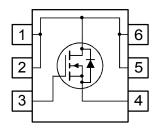
These N-Channel Logic Level MOSFETs are produced using Fairchild Semiconductor's advanced Power Trench process that has been especially tailored to minimize the on-state resistance and yet maintain superior switching performance.

These devices are well suited for low voltage and battery powered applications where low in-line power loss and fast switching are required.

Features

- 4.2 A, 30 V. $R_{DS(ON)} = 65 \text{ m}\Omega$ @ $V_{GS} = 10 \text{ V}$ $R_{DS(ON)} = 95 \text{ m}\Omega$ @ $V_{GS} = 4.5 \text{ V}$
- High performance trench technology for extremely low $R_{\mbox{\scriptsize DS(ON)}}$
- Low gate charge (9.4 nC typical)
- · High power and current handling capability





Absolute Maximum Ratings TA=25°C unless otherwise noted

Symbol	Parameter		Ratings	Units
V _{DSS}	Drain-Source Voltage		30	V
V_{GSS}	Gate-Source Voltage		±20	V
I _D	Drain Current - Continuous	(Note 1a)	4.2	А
	- Pulsed		20	
P_D	Maximum Power Dissipation	(Note 1a)	1.6	W
		(Note 1b)	0.8	
T _J , T _{STG}	Operating and Storage Junction Tem	perature Range	-55 to +150	°C

Thermal Characteristics

$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	(Note 1a)	78	°C/W
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	(Note 1)	30	°C/W

Package Marking and Ordering Information

Device Marking	Device Reel Size		Tape width	Quantity	
.454	Si3454DV	7"	8mm	3000 units	

Symbol Parameter		Test Conditions	Min	Тур	Max	Units
		Tool Conditions		. 76	max	011110
	acteristics		1	ı	1	1
BV _{DSS}	Drain–Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_{D} = 250 \mu\text{A}$	30			V
<u>ΔBV_{DSS}</u> ΔT _J	Breakdown Voltage Temperature Coefficient	I_D = 250 μ A, Referenced to 25°C		20		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 30 \text{ V}, \ V_{GS} = 0 \text{ V}$			1	μΑ
		V _{DS} = 30 V, V _{GS} = 0 V, T _J =70°C			25	
I _{GSSF}	Gate-Body Leakage, Forward	V _{GS} = 20 V, V _{DS} = 0 V			100	nA
I _{GSSR}	Gate-Body Leakage, Reverse	V _{GS} = -20 V, V _{DS} = 0 V			-100	nA
On Char	acteristics (Note 2)					
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	1	1.5	2	V
$\Delta V_{GS(th)} \over \Delta T_J$	Gate Threshold Voltage Temperature Coefficient	I_D = 250 μ A, Referenced to 25°C		- 4		mV/°C
R _{DS(on)}	Static Drain–Source On–Resistance	$V_{GS} = 10 \text{ V}, I_D = 4.2 \text{ A}$ $V_{GS} = 4.5 \text{ V}, I_D = 3.4 \text{ A}$		33 44	65 95	mΩ
I _{D(on)}	On–State Drain Current	V _{GS} = 10 V, V _{DS} = 5 V	15			Α
g _{FS}	Forward Transconductance	V _{DS} = 10 V, I _D = 4.2 A		10		S
Dvnamio	Characteristics	1	_1	I	ı	ı
C _{iss}	Input Capacitance	V _{DS} = 15 V, V _{GS} = 0 V,		460		pF
Coss	Output Capacitance	f = 1.0 MHz		115		pF
C _{rss}	Reverse Transfer Capacitance			45		pF
Switchin	g Characteristics (Note 2)			•	•	
t _{d(on)}	Turn-On Delay Time	$V_{DS} = 15 \text{ V}, I_{D} = 1 \text{ A},$		5	20	nS
t _r	Turn-On Rise Time	V_{GS} = 10 V, R_{GEN} = 6 Ω		8	30	nS
$t_{d(off)}$	Turn-Off Delay Time			17	35	nS
t _f	Turn–Off Fall Time			13	20	nS
t _{rr}	Source-Drain Reverse Recovery Time	I _F = 1.7 A, di/dt = 100 A/uS			80	nS
Qg	Total Gate Charge	$V_{DS} = 10 \text{ V}, I_D = 4.2 \text{ A},$		9.4	15	nC
Q _{gs}	Gate-Source Charge	V _{GS} = 10 V		1.2		nC
Q_{gd}	Gate-Drain Charge			1.1		nC
Drain-S	ource Diode Characteristics	and Maximum Ratings				
ls	Maximum Continuous Drain-Source				1.7	Α
V _{SD}	Drain–Source Diode Forward Voltage	V _{GS} = 0 V, I _S = 1.7 A (Note 2)			1.2	V

Notes:

- R_{0,JA} is the sum of the junction-to-case and case-to-ambient resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R_{0,C} is guaranteed by design while R_{0,CA} is determined by the user's board design.
 - a. 78°C/W when mounted on a 1in^2 pad of 2oz copper on FR-4 board.
 - b. 156°C/W when mounted on a minimum pad.
- 2. Pulse Test: Pulse Width $\leq 300~\mu s,~Duty~Cycle \leq 2.0\%$

Typical Characteristics
Figure 1. On-Region Characteristics. Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.
Figure 3. On-Resistance Variation Figure 4. On-Resistance Variation with withTemperature. Gate-to-Source Voltage.
Figure 5. Transfer Characteristics. Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.



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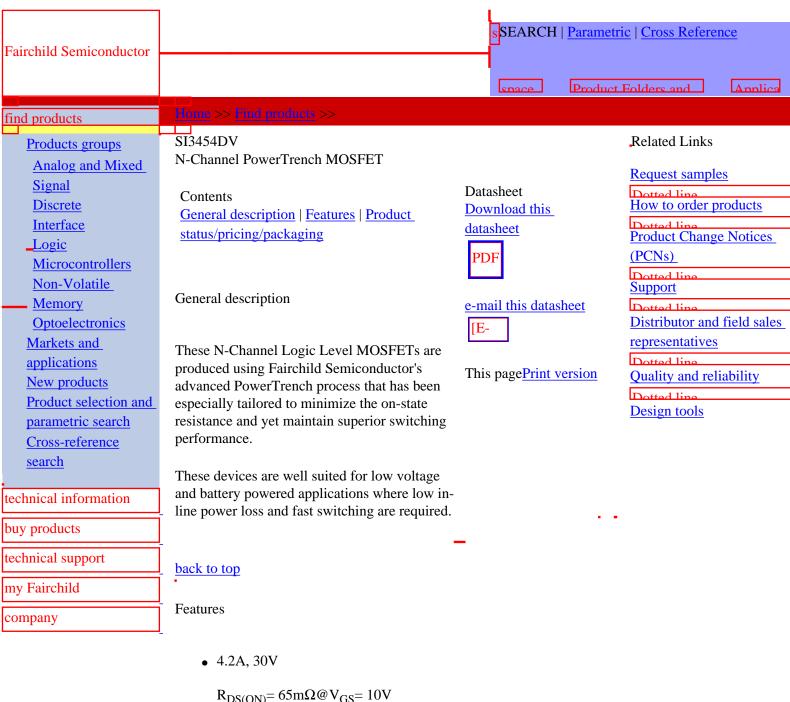
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Rev. H4



 $R_{DS(ON)} = 65 \text{m} \Omega @ V_{GS} = 10 \text{V}$

 $R_{DS(ON)} = 95 \text{m}\Omega@V_{GS} = 4.5V$

- $\bullet \ \ \mbox{High performance trench technology for} \\ \mbox{extremely low } R_{DS(ON)}$
- Low gate charge (9.4 nC typical)
- High power and current handling capability

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Product status/pricing/packaging

Product	Product status	Pricing*	Package type	Leads	Package marking	Packing method
SI3454DV	Full Production	\$0.346	SuperSOT	6	.454	TAPE REEL

Product Folder - Fairchild P/N SI3454DV - N-Channel PowerTrench MOSFET
* 1,000 piece Budgetary Pricing
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